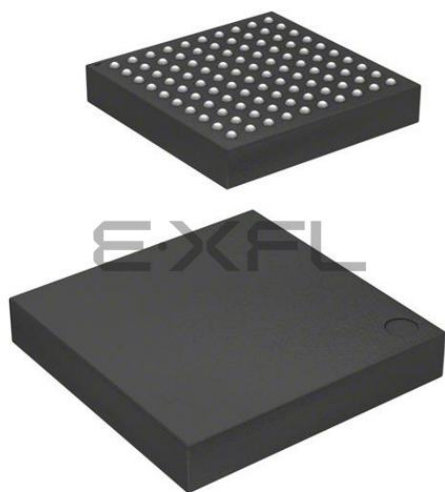




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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	RXv2
Core Size	32-Bit Single-Core
Speed	54MHz
Connectivity	CANbus, EBI/EMI, I ² C, IrDA, SCI, SD/SDIO, SPI, SSI, USB OTG
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	79
Program Memory Size	384KB (384K x 8)
Program Memory Type	FLASH
EEPROM Size	8K x 8
RAM Size	64K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 5.5V
Data Converters	A/D 24x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-TFLGA
Supplier Device Package	100-TFLGA (5.5x5.5)
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f52317adla-20

Table 1.1 Outline of Specifications (3/4)

Classification	Module/Function	Description
Timers	Independent watchdog timer (IWDtA)	14 bits × 1 channel - Count clock: Dedicated low-speed on-chip oscillator for the IWDtA Frequency divided by 1, 16, 32, 64, 128, or 256
	Realtime clock (RTCe)	- Clock source: Sub-clock - Time/calendar - Interrupts: Alarm interrupt, periodic interrupt, and carry interrupt - Time-capture facility for three values
	Low power timer (LPT)	16 bits × 1 channel - Clock source: Sub-clock, Dedicated low-speed on-chip oscillator for the IWDtA Frequency divided by 2, 4, 8, 16, or 32
	8-bit timer (TMR)	(8 bits × 2 channels) × 2 units - Seven internal clocks (PCLK/1, PCLK/2, PCLK/8, PCLK/32, PCLK/64, PCLK/1024, and PCLK/8192) and an external clock can be selected - Pulse output and PWM output with any duty cycle are available - Two channels can be cascaded and used as a 16-bit timer
Communication functions	Serial communications interfaces (SCIg, SCIlh)	7 channels (channel 0, 1, 5, 6, 8, 9: SCIg, channel 12: SCIlh) - SCIg - Serial communications modes: Asynchronous, clock synchronous, and smart-card interface - Multi-processor function - On-chip baud rate generator allows selection of the desired bit rate - Choice of LSB-first or MSB-first transfer - Average transfer rate clock can be input from TMR timers for SCI5, SCI6, and SCI12 - Start-bit detection: Level or edge detection is selectable. - Simple I²C - Simple SPI 9-bit transfer mode - Bit rate modulation - Event linking by the ELC (only on channel 5) - SCIlh (The following functions are added to SCIg) - Supports the serial communications protocol, which contains the start frame and information frame - Supports the LIN format
	IrDA interface (IRDA)	1 channel (SCI5 used) - Supports encoding/decoding of waveforms conforming to IrDA standard 1.0
	I ² C bus interface (RIICa)	1 channel - Communications formats: I²C bus format/SMBus format - Master mode or slave mode selectable - Supports fast mode
	Serial peripheral interface (RSPIa)	1 channel - Transfer facility - Using the MOSI (master out, slave in), MISO (master in, slave out), SSL (slave select), and RSPCK (RSPI clock) enables serial transfer through SPI operation (four lines) or clock-synchronous operation (three lines) - Capable of handling serial transfer as a master or slave - Data formats - Choice of LSB-first or MSB-first transfer - The number of bits in each transfer can be changed to 8, 9, 10, 11, 12, 13, 14, 15, 16, 20, 24, or 32 bits. 128-bit buffers for transmission and reception - Up to four frames can be transmitted or received in a single transfer operation (with each frame having up to 32 bits) - Double buffers for both transmission and reception
	USB 2.0 host/function module (USBd)	- USB Device Controller (UDC) and transceiver for USB 2.0 are incorporated. - Host/function module: 1 port - Compliant with USB version 2.0 - Transfer speed: Full-speed (12 Mbps), low-speed (1.5 Mbps) - OTG (ON-The-Go) is supported. - Isochronous transfer is supported. - BC1.2 (Battery Charging Specification Revision 1.2) is supported. - Internal power supply for USB (allows operation without external power input to the VCC_USB pin when VCC = 4.0 to 5.5V)
	CAN module (RSCAN)	1 channel - Compliance with the ISO11898-1 specification (standard frame and extended frame) 16 Message boxes

Table 1.2 Comparison of Functions for Different Packages

Module/Functions		RX230 Group			RX231 Group		
		100 Pins	64 Pins	48 Pins	100 Pins	64 Pins	48 Pins
External bus	External bus	16 bit	Not supported		16 bit	Not supported	
Interrupts	External interrupts	NMI, IRQ0 to IRQ7	NMI, IRQ0, IRQ1, IRQ4 to IRQ7	NMI, IRQ0, IRQ1, IRQ4 to IRQ7	NMI, IRQ0 to IRQ7	NMI, IRQ0, IRQ1, IRQ4 to IRQ7	NMI, IRQ0, IRQ1, IRQ4 to IRQ7
DMA	DMA controller	4 channels (DMAC0 to DMAC3)			4 channels (DMAC0 to DMAC3)		
	Data transfer controller	Available			Available		
Timers	16-bit timer pulse unit	6 channels (TPU0 to TPU5)			6 channels (TPU0 to TPU5)		
	Multi-function timer pulse unit 2	6 channels (MTU0 to MTU5)			6 channels (MTU0 to MTU5)		
	Port output enable 2	POE0# to POE3#, POE8#			POE0# to POE3#, POE8#		
	8-bit timer	2 channels× 2 units			2 channels× 2 units		
	Compare match timer	2 channels× 2 units			2 channels× 2 units		
	Low power timer	1 channel			1 channel		
	Realtime clock	Available		Not supported	Available		Not supported
	Watchdog timer	Available			Available		
	Independent watchdog timer	Available			Available		
Communication functions	Serial communications interfaces (SCIg)	6 channels (SCI0, 1, 5, 6, 8, 9)	5 channels (SCI1, 5, 6, 8, 9)	4 channels (SCI1, 5, 6, 8)	6 channels (SCI0, 1, 5, 6, 8, 9)	5 channels (SCI1, 5, 6, 8, 9)	4 channels (SCI1, 5, 6, 8)
	IrDA interface	1 channel (SCI5)			1 channel (SCI5)		
	Serial communications interfaces (SCIh)	1 channel (SCI12)			1 channel (SCI12)		
	I ² C bus interface	1 channel			1 channel		
	CAN module	Not supported			1 channel*1		
	Serial peripheral interface	1 channel			1 channel		
	USB 2.0 host/function module	Not supported			1 channel		
	Serial sound interface	1 channel			1 channel		
	SD Host Interface	Not supported			1 channel*1		Not supported
Capacitive touch sensing unit		24 channels	10 channels	6 channels	24 channels	10 channels	6 channels
12-bit A/D converter (including high-precision channels)		24 channels (8 channels)	12 channels (6 channels)	8 channels (4 channels)	24 channels (8 channels)	12 channels (6 channels)	8 channels (4 channels)
Temperature sensor		Available			Available		
D/A converter		2 channels		Not supported	2 channels		Not supported
CRC calculator		Available			Available		
Event link controller		Available			Available		
Comparator B		4 channels			4 channels		
Packages		100-pin TFLGA 100-pin LFQFP	64-pin WFLGA 64-pin HWQFN 64-pin LFQFP	48-pin HWQFN 48-pin LFQFP	100-pin TFLGA 100-pin LFQFP	64-pin WFLGA 64-pin HWQFN 64-pin LFQFP	48-pin HWQFN 48-pin LFQFP

Note 1. Only for chip version B

1.3 Block Diagram

Figure 1.2 shows a block diagram.

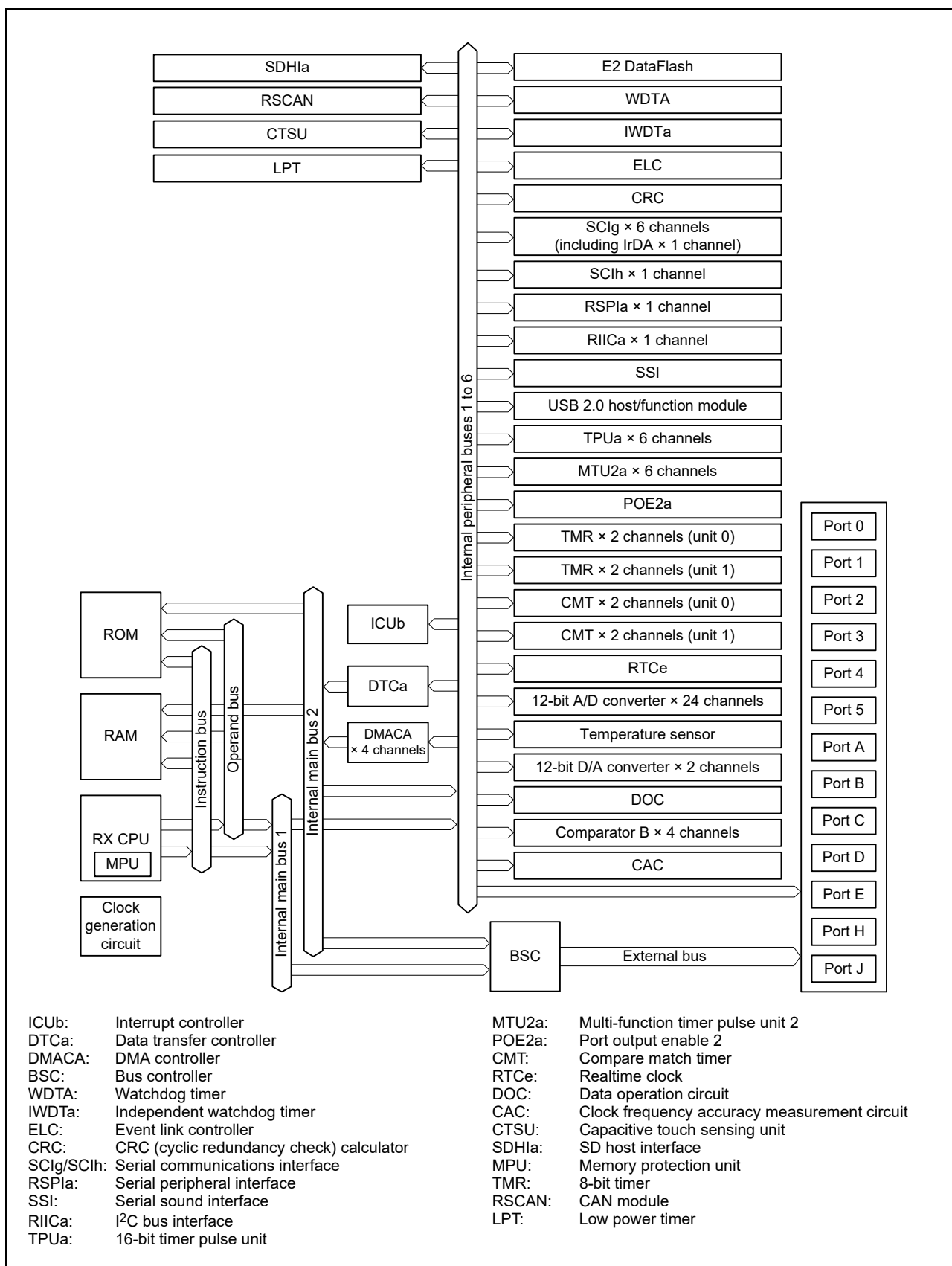


Figure 1.2 Block Diagram

Table 1.6 List of Pins and Pin Functions (100-Pin TFLGA) (2/3)

Pin No.	Power Supply, Clock, System Control	I/O Port	External Bus	Timers (MTU, TPU, TMR, RTC, CMT, POE, CAC)	Communications (SCI, RSPI, RIIIC, RSCAN, USB, SSI)	Memory Interface (SDHI)	Touch sensing	Others
E8		PA4	A4	MTIOC5U/MTCLKA/TMRI0/TIOCA1	TXD5/SMOSI5/SSDA5/SSLA0/SSITXD0/IRTXD5			IRQ5 / CVREFB1
E9		PA5	A5	TIOCB1	RSPCKA			
E10		PA3	A3	MTIOC0D/MTCLKD/TIOC0D/TCLKB	RXD5/SMISO5/SSCL5/SSIRXD0/IRRXD5			IRQ6 /CMPB1
F1	EXTAL	P36						
F2	VCC							
F3	UPSEL	P35						NMI
F4		P32		MTIOC0C/TMO3/TIOCC0/RTCOUT/RTCIC2	TXD6/SMOSI6/SSDA6/USB0_VBUSEN			IRQ2
F5		P12		TMCI1	SCL			IRQ2
F6		PB3	A11	MTIOC0A/MTIOC4A/TMO0/POE3#/TIOC0D/TCLKD	SCK6	SDHI_W P		
F7		PB2	A10	TIOCC3/TCLKC	CTS6#/RTS6#/SS6#			
F8		PB0	A8	MTIC5W/TIOCA3	RXD6/SMISO6/SSCL6/RSPCKA	SDHI_C MD		
F9		PA7	A7	TIOCB2	MISOA			
F10	VSS							
G1		P33		MTIOC0D/TMRI3/POE3#/TIOC0D	RXD6/SMISO6/SSCL6		TS1	IRQ3
G2		P31		MTIOC4D/TMCI2/RTCIC1	CTS1#/RTS1#/SS1#/SSISCK0			IRQ1
G3		P30		MTIOC4B/TMRI3/POE8#/RTCIC0	RXD1/SMISO1/SSCL1/AUDIO_MCLK			IRQ0/CMPOB3
G4		P27	CS3#	MTIOC2B/TMCI3	SCK1/ SSIWS0		TS2	CVREFB3
G5	BCLK	P53					TS17	
G6		P52	RD#				TS18	
G7		PB5	A13	MTIOC2A/MTIOC1B/TMRI1/POE1#/TIOCB4	SCK9/USB0_VBUS	SDHI_CD		
G8		PB4	A12	TIOCA4	CTS9#/RTS9#/SS9#			
G9		PB1	A9	MTIOC0C/MTIOC4C/TMCI0/TIOCB3	TXD6/SMOSI6/SSDA6	SDHI_CL K		IRQ4/CMPOB1
G10	VCC							
H1		P26	CS2#	MTIOC2A/TMO1	TXD1/SMOSI1/SSDA1/SSIRXD0		TS3	CMPB3
H2		P25	CS1#	MTIOC4C/MTCLKB/TIOCA4			TS4	ADTRG0#
H3		P16		MTIOC3C/MTIOC3D/TMO2/TIOCB1/TCLKC/RTCOUT	TXD1/SMOSI1/SSDA1/MOSIA/SCL/USB0_VBUS/USB0_VBUSEN/USB0_OVRCURB			IRQ6/ADTRG0#
H4		P15		MTIOC0B/MTCLKB/TMCI2/TIOCB2/TCLKB	RXD1/SMISO1/SSCL1/CRXD0		TS12	IRQ5/CMPB2
H5		P55	WAIT#	MTIOC4D/TMO3	CRXD0		TS15	
H6		P54	ALE	MTIOC4B/TMCI1	CTXD0		TS16	
H7	UB	PC7	A23/CS0#	MTIOC3A/MTCLKB/TMO2	TXD8/SMOSI8/SSDA8/MISOA			CACREF
H8		PC6	A22/CS1#	MTIOC3C/MTCLKA/TMCI2	RXD8/SMISO8/SSCL8/MOSIA		TS22	
H9		PB6	A14	MTIOC3D/TIOCA5	RXD9/SMISO9/SSCL9	SDHI_D1		
H10		PB7	A15	MTIOC3B/TIOCB5	TXD9/SMOSI9/SSDA9	SDHI_D2		
J1		P24	CS0#	MTIOC4A/MTCLKA/TMRI1/TIOCB4	USB0_VBUSEN		TS5	
J2		P21		MTIOC1B/TMCI0/TIOCA3	RXD0/SMISO0/SSCL0/USB0_EXICEN/SSIWS0		TS8	
J3		P17		MTIOC3A/MTIOC3B/TMO1/POE8#/TIOCB0/TCLKD	SCK1/MISOA/SDA/SSITXD0			IRQ7/CMPOB2
J4		P13		MTIOC0B/TMO3/TIOCA5	SDA			IRQ3
J5	VSS_USB*1	PH0*1						CACREF*1

Table 4.1 List of I/O Registers (Address Order) (5/33)

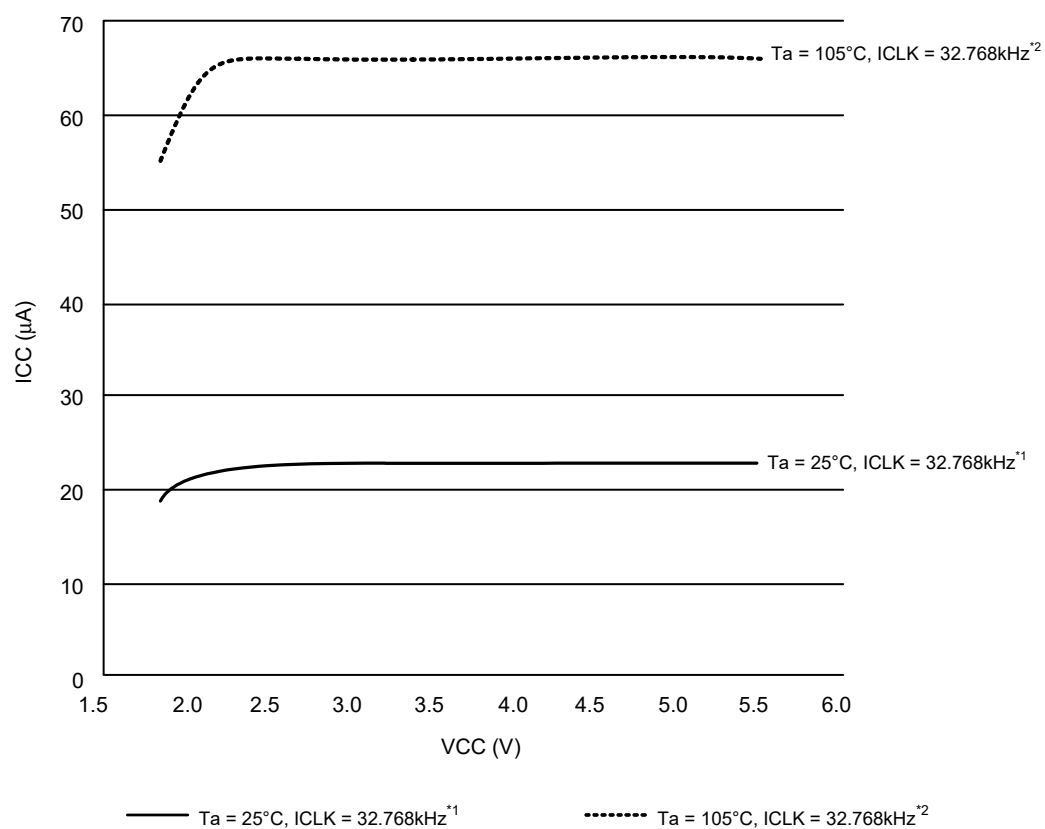
Address	Module Symbol	Register Name	Register Symbol	Number of Bits	Access Size	Number of Access Cycles	
						ICLK ≥ PCLK	ICLK < PCLK
0008 8100h	TPU	Timer Start Register	TSTR	8	8	2 or 3 PCLKB	2 ICLK
0008 8101h	TPU	Timer Synchronous Register	TSYR	8	8	2 or 3 PCLKB	2 ICLK
0008 8108h	TPU0	Noise Filter Control Register	NFCR	8	8	2 or 3 PCLKB	2 ICLK
0008 8109h	TPU1	Noise Filter Control Register	NFCR	8	8	2 or 3 PCLKB	2 ICLK
0008 810Ah	TPU2	Noise Filter Control Register	NFCR	8	8	2 or 3 PCLKB	2 ICLK
0008 810Bh	TPU3	Noise Filter Control Register	NFCR	8	8	2 or 3 PCLKB	2 ICLK
0008 810Ch	TPU4	Noise Filter Control Register	NFCR	8	8	2 or 3 PCLKB	2 ICLK
0008 810Dh	TPU5	Noise Filter Control Register	NFCR	8	8	2 or 3 PCLKB	2 ICLK
0008 8110h	TPU0	Timer Control Register	TCR	8	8	2 or 3 PCLKB	2 ICLK
0008 8111h	TPU0	Timer Mode Register	TMDR	8	8	2 or 3 PCLKB	2 ICLK
0008 8112h	TPU0	Timer I/O Control Register H	TIORH	8	8	2 or 3 PCLKB	2 ICLK
0008 8113h	TPU0	Timer I/O Control Register L	TIORL	8	8	2 or 3 PCLKB	2 ICLK
0008 8114h	TPU0	Timer Interrupt Enable Register	TIER	8	8	2 or 3 PCLKB	2 ICLK
0008 8115h	TPU0	Timer Status Register	TSR	8	8	2 or 3 PCLKB	2 ICLK
0008 8116h	TPU0	Timer Counter	TCNT	16	16	2 or 3 PCLKB	2 ICLK
0008 8118h	TPU0	Timer General Register A	TGRA	16	16	2 or 3 PCLKB	2 ICLK
0008 811Ah	TPU0	Timer General Register B	TGRB	16	16	2 or 3 PCLKB	2 ICLK
0008 811Ch	TPU0	Timer General Register C	TGRC	16	16	2 or 3 PCLKB	2 ICLK
0008 811Eh	TPU0	Timer General Register D	TGRD	16	16	2 or 3 PCLKB	2 ICLK
0008 8120h	TPU1	Timer Control Register	TCR	8	8	2 or 3 PCLKB	2 ICLK
0008 8121h	TPU1	Timer Mode Register	TMDR	8	8	2 or 3 PCLKB	2 ICLK
0008 8122h	TPU1	Timer I/O Control Register	TIOR	8	8	2 or 3 PCLKB	2 ICLK
0008 8124h	TPU1	Timer Interrupt Enable Register	TIER	8	8	2 or 3 PCLKB	2 ICLK
0008 8125h	TPU1	Timer Status Register	TSR	8	8	2 or 3 PCLKB	2 ICLK
0008 8126h	TPU1	Timer Counter	TCNT	16	16	2 or 3 PCLKB	2 ICLK
0008 8128h	TPU1	Timer General Register A	TGRA	16	16	2 or 3 PCLKB	2 ICLK
0008 812Ah	TPU1	Timer General Register B	TGRB	16	16	2 or 3 PCLKB	2 ICLK
0008 8130h	TPU2	Timer Control Register	TCR	8	8	2 or 3 PCLKB	2 ICLK
0008 8131h	TPU2	Timer Mode Register	TMDR	8	8	2 or 3 PCLKB	2 ICLK
0008 8132h	TPU2	Timer I/O Control Register	TIOR	8	8	2 or 3 PCLKB	2 ICLK
0008 8134h	TPU2	Timer Interrupt Enable Register	TIER	8	8	2 or 3 PCLKB	2 ICLK
0008 8135h	TPU2	Timer Status Register	TSR	8	8	2 or 3 PCLKB	2 ICLK
0008 8136h	TPU2	Timer Counter	TCNT	16	16	2 or 3 PCLKB	2 ICLK
0008 8138h	TPU2	Timer General Register A	TGRA	16	16	2 or 3 PCLKB	2 ICLK
0008 813Ah	TPU2	Timer General Register B	TGRB	16	16	2 or 3 PCLKB	2 ICLK
0008 8140h	TPU3	Timer Control Register	TCR	8	8	2 or 3 PCLKB	2 ICLK
0008 8141h	TPU3	Timer Mode Register	TMDR	8	8	2 or 3 PCLKB	2 ICLK
0008 8142h	TPU3	Timer I/O Control Register H	TIORH	8	8	2 or 3 PCLKB	2 ICLK
0008 8143h	TPU3	Timer I/O Control Register L	TIORL	8	8	2 or 3 PCLKB	2 ICLK
0008 8144h	TPU3	Timer Interrupt Enable Register	TIER	8	8	2 or 3 PCLKB	2 ICLK
0008 8145h	TPU3	Timer Status Register	TSR	8	8	2 or 3 PCLKB	2 ICLK
0008 8146h	TPU3	Timer Counter	TCNT	16	16	2 or 3 PCLKB	2 ICLK
0008 8148h	TPU3	Timer General Register A	TGRA	16	16	2 or 3 PCLKB	2 ICLK
0008 814Ah	TPU3	Timer General Register B	TGRB	16	16	2 or 3 PCLKB	2 ICLK
0008 814Ch	TPU3	Timer General Register C	TGRC	16	16	2 or 3 PCLKB	2 ICLK
0008 814Eh	TPU3	Timer General Register D	TGRD	16	16	2 or 3 PCLKB	2 ICLK
0008 8150h	TPU4	Timer Control Register	TCR	8	8	2 or 3 PCLKB	2 ICLK
0008 8151h	TPU4	Timer Mode Register	TMDR	8	8	2 or 3 PCLKB	2 ICLK
0008 8152h	TPU4	Timer I/O Control Register	TIOR	8	8	2 or 3 PCLKB	2 ICLK
0008 8154h	TPU4	Timer Interrupt Enable Register	TIER	8	8	2 or 3 PCLKB	2 ICLK
0008 8155h	TPU4	Timer Status Register	TSR	8	8	2 or 3 PCLKB	2 ICLK
0008 8156h	TPU4	Timer Counter	TCNT	16	16	2 or 3 PCLKB	2 ICLK

Table 4.1 List of I/O Registers (Address Order) (12/33)

Address	Module Symbol	Register Name	Register Symbol	Number of Bits	Access Size	Number of Access Cycles	
						ICLK ≥ PCLK	ICLK < PCLK
0008 A131h	SCI9	Receive Data Register L	RDRL	8	8	2 or 3 PCLKB	2 ICLK
0008 A132h	SCI9	Modulation Duty Register	MDDR	8	8	2 or 3 PCLKB	2 ICLK
0008 A500h	SSI0	Control Register	SSICR	32	32	2 or 3 PCLKB	2 ICLK
0008 A504h	SSI0	Status Register	SSISR	32	32	2 or 3 PCLKB	2 ICLK
0008 A510h	SSI0	FIFO Control Register	SSIFCR	32	32	2 or 3 PCLKB	2 ICLK
0008 A514h	SSI0	FIFO Status Register	SSIFSR	32	32	2 or 3 PCLKB	2 ICLK
0008 A518h	SSI0	Transmit FIFO Data Register	SSIFTDR	32	32	2 or 3 PCLKB	2 ICLK
0008 A51Ch	SSI0	Receive FIFO Data Register	SSIFRDR	32	32	2 or 3 PCLKB	2 ICLK
0008 A520h	SSI0	TDM Mode Register	SSITDMR	32	32	2 or 3 PCLKB	2 ICLK
0008 AC00h	SDHI	Command Register	SDCMD	32	32	3 or 4 PCLKB cycles when reading, 2 or 3 PCLKB cycles when writing	3 ICLK cycles when reading, 2 ICLK cycles when writing
0008 AC08h	SDHI	Argument Register	SDARG	32	32	3 or 4 PCLKB cycles when reading, 2 or 3 PCLKB cycles when writing	3 ICLK cycles when reading, 2 ICLK cycles when writing
0008 AC10h	SDHI	Data Stop Register	SDSTOP	32	32	3 or 4 PCLKB cycles when reading, 2 or 3 PCLKB cycles when writing	3 ICLK cycles when reading, 2 ICLK cycles when writing
0008 AC14h	SDHI	Block Count Register	SDBLKCNT	32	32	3 or 4 PCLKB cycles when reading, 2 or 3 PCLKB cycles when writing	3 ICLK cycles when reading, 2 ICLK cycles when writing
0008 AC18h	SDHI	Response Register 10	SDRSP10	32	32	3 or 4 PCLKB cycles when reading, 2 or 3 PCLKB cycles when writing	3 ICLK cycles when reading, 2 ICLK cycles when writing
0008 AC20h	SDHI	Response Register 32	SDRSP32	32	32	3 or 4 PCLKB cycles when reading, 2 or 3 PCLKB cycles when writing	3 ICLK cycles when reading, 2 ICLK cycles when writing
0008 AC28h	SDHI	Response Register 54	SDRSP54	32	32	3 or 4 PCLKB cycles when reading, 2 or 3 PCLKB cycles when writing	3 ICLK cycles when reading, 2 ICLK cycles when writing
0008 AC30h	SDHI	Response Register 76	SDRSP76	32	32	3 or 4 PCLKB cycles when reading, 2 or 3 PCLKB cycles when writing	3 ICLK cycles when reading, 2 ICLK cycles when writing
0008 AC38h	SDHI	SD Status Register 1	SDSTS1	32	32	3 or 4 PCLKB cycles when reading, 2 or 3 PCLKB cycles when writing	3 ICLK cycles when reading, 2 ICLK cycles when writing
0008 AC3Ch	SDHI	SD Status Register 2	SDSTS2	32	32	3 or 4 PCLKB cycles when reading, 2 or 3 PCLKB cycles when writing	3 ICLK cycles when reading, 2 ICLK cycles when writing
0008 AC40h	SDHI	SD Interrupt Mask Register 1	SDIMSK1	32	32	3 or 4 PCLKB cycles when reading, 2 or 3 PCLKB cycles when writing	3 ICLK cycles when reading, 2 ICLK cycles when writing

Table 4.1 List of I/O Registers (Address Order) (28/33)

Address	Module Symbol	Register Name	Register Symbol	Number of Bits	Access Size	Number of Access Cycles	
						ICLK ≥ PCLK	ICLK < PCLK
000A 8446h	RSCAN	Receive Rule Entry Register 13CH	GAFLPH13	16	16	2 or 3 PCLKB	2 ICLK
000A 8446h	RSCAN	Receive Buffer Register 10BH	RMPTR10	16	16	2 or 3 PCLKB	2 ICLK
000A 8448h	RSCAN	Receive Rule Entry Register 14AL	GAFLIDL14	16	16	2 or 3 PCLKB	2 ICLK
000A 8448h	RSCAN	Receive Buffer Register 10CL	RMDF010	16	16	2 or 3 PCLKB	2 ICLK
000A 844Ah	RSCAN	Receive Rule Entry Register 14AH	GAFLIDH14	16	16	2 or 3 PCLKB	2 ICLK
000A 844Ah	RSCAN	Receive Buffer Register 10CH	RMDF110	16	16	2 or 3 PCLKB	2 ICLK
000A 844Ch	RSCAN	Receive Rule Entry Register 14BL	GAFLML14	16	16	2 or 3 PCLKB	2 ICLK
000A 844Ch	RSCAN	Receive Buffer Register 10DL	RMDF210	16	16	2 or 3 PCLKB	2 ICLK
000A 844Eh	RSCAN	Receive Rule Entry Register 14BH	GAFLMH14	16	16	2 or 3 PCLKB	2 ICLK
000A 844Eh	RSCAN	Receive Buffer Register 10DH	RMDF310	16	16	2 or 3 PCLKB	2 ICLK
000A 8450h	RSCAN	Receive Rule Entry Register 14CL	GAFLPL14	16	16	2 or 3 PCLKB	2 ICLK
000A 8450h	RSCAN	Receive Buffer Register 11AL	RMIDL11	16	16	2 or 3 PCLKB	2 ICLK
000A 8452h	RSCAN	Receive Rule Entry Register 14CH	GAFLPH14	16	16	2 or 3 PCLKB	2 ICLK
000A 8452h	RSCAN	Receive Buffer Register 11AH	RMIDH11	16	16	2 or 3 PCLKB	2 ICLK
000A 8454h	RSCAN	Receive Rule Entry Register 15AL	GAFLIDL15	16	16	2 or 3 PCLKB	2 ICLK
000A 8454h	RSCAN	Receive Buffer Register 11BL	RMTS11	16	16	2 or 3 PCLKB	2 ICLK
000A 8456h	RSCAN	Receive Rule Entry Register 15AH	GAFLIDH15	16	16	2 or 3 PCLKB	2 ICLK
000A 8456h	RSCAN	Receive Buffer Register 11BH	RMPTR11	16	16	2 or 3 PCLKB	2 ICLK
000A 8458h	RSCAN	Receive Rule Entry Register 15BL	GAFLML15	16	16	2 or 3 PCLKB	2 ICLK
000A 8458h	RSCAN	Receive Buffer Register 11CL	RMDF011	16	16	2 or 3 PCLKB	2 ICLK
000A 845Ah	RSCAN	Receive Rule Entry Register 15BH	GAFLMH15	16	16	2 or 3 PCLKB	2 ICLK
000A 845Ah	RSCAN	Receive Buffer Register 11CH	RMDF111	16	16	2 or 3 PCLKB	2 ICLK
000A 845Ch	RSCAN	Receive Rule Entry Register 15CL	GAFLPL15	16	16	2 or 3 PCLKB	2 ICLK
000A 845Ch	RSCAN	Receive Buffer Register 11DL	RMDF211	16	16	2 or 3 PCLKB	2 ICLK
000A 845Eh	RSCAN	Receive Rule Entry Register 15CH	GAFLPH15	16	16	2 or 3 PCLKB	2 ICLK
000A 845Eh	RSCAN	Receive Buffer Register 11DH	RMDF311	16	16	2 or 3 PCLKB	2 ICLK
000A 8460h	RSCAN	Receive Buffer Register 12AL	RMIDL12	16	16	2 or 3 PCLKB	2 ICLK
000A 8462h	RSCAN	Receive Buffer Register 12AH	RMIDH12	16	16	2 or 3 PCLKB	2 ICLK
000A 8464h	RSCAN	Receive Buffer Register 12BL	RMTS12	16	16	2 or 3 PCLKB	2 ICLK
000A 8466h	RSCAN	Receive Buffer Register 12BH	RMPTR12	16	16	2 or 3 PCLKB	2 ICLK
000A 8468h	RSCAN	Receive Buffer Register 12CL	RMDF012	16	16	2 or 3 PCLKB	2 ICLK
000A 846Ah	RSCAN	Receive Buffer Register 12CH	RMDF112	16	16	2 or 3 PCLKB	2 ICLK
000A 846Ch	RSCAN	Receive Buffer Register 12DL	RMDF212	16	16	2 or 3 PCLKB	2 ICLK
000A 846Eh	RSCAN	Receive Buffer Register 12DH	RMDF312	16	16	2 or 3 PCLKB	2 ICLK
000A 8470h	RSCAN	Receive Buffer Register 13AL	RMIDL13	16	16	2 or 3 PCLKB	2 ICLK
000A 8472h	RSCAN	Receive Buffer Register 13AH	RMIDH13	16	16	2 or 3 PCLKB	2 ICLK
000A 8474h	RSCAN	Receive Buffer Register 13BL	RMTS13	16	16	2 or 3 PCLKB	2 ICLK
000A 8476h	RSCAN	Receive Buffer Register 13BH	RMPTR13	16	16	2 or 3 PCLKB	2 ICLK
000A 8478h	RSCAN	Receive Buffer Register 13CL	RMDF013	16	16	2 or 3 PCLKB	2 ICLK
000A 847Ah	RSCAN	Receive Buffer Register 13CH	RMDF113	16	16	2 or 3 PCLKB	2 ICLK
000A 847Ch	RSCAN	Receive Buffer Register 13DL	RMDF213	16	16	2 or 3 PCLKB	2 ICLK
000A 847Eh	RSCAN	Receive Buffer Register 13DH	RMDF313	16	16	2 or 3 PCLKB	2 ICLK
000A 8480h	RSCAN	Receive Buffer Register 14AL	RMIDL14	16	16	2 or 3 PCLKB	2 ICLK
000A 8482h	RSCAN	Receive Buffer Register 14AH	RMIDH14	16	16	2 or 3 PCLKB	2 ICLK
000A 8484h	RSCAN	Receive Buffer Register 14BL	RMTS14	16	16	2 or 3 PCLKB	2 ICLK
000A 8486h	RSCAN	Receive Buffer Register 14BH	RMPTR14	16	16	2 or 3 PCLKB	2 ICLK
000A 8488h	RSCAN	Receive Buffer Register 14CL	RMDF014	16	16	2 or 3 PCLKB	2 ICLK
000A 848Ah	RSCAN	Receive Buffer Register 14CH	RMDF114	16	16	2 or 3 PCLKB	2 ICLK
000A 848Ch	RSCAN	Receive Buffer Register 14DL	RMDF214	16	16	2 or 3 PCLKB	2 ICLK
000A 848Eh	RSCAN	Receive Buffer Register 14DH	RMDF314	16	16	2 or 3 PCLKB	2 ICLK
000A 8490h	RSCAN	Receive Buffer Register 15AL	RMIDL15	16	16	2 or 3 PCLKB	2 ICLK
000A 8492h	RSCAN	Receive Buffer Register 15AH	RMIDH15	16	16	2 or 3 PCLKB	2 ICLK



Note 1. All peripheral operations except any BGO operation are operating normally. Indicates the average of the typical samples through actual measurement during product evaluation.

Note 2. All peripheral operations except any BGO operation are operating at maximum. Indicates the average of the upper-limit samples through actual measurement during product evaluation.

Figure 5.3 Voltage Dependency in Low-Speed Operating Mode (Reference Data)

5.2.1 Normal I/O Pin Output Characteristics (1)

Figure 5.8 to Figure 5.12 show the characteristics when normal output is selected by the drive capacity control register.

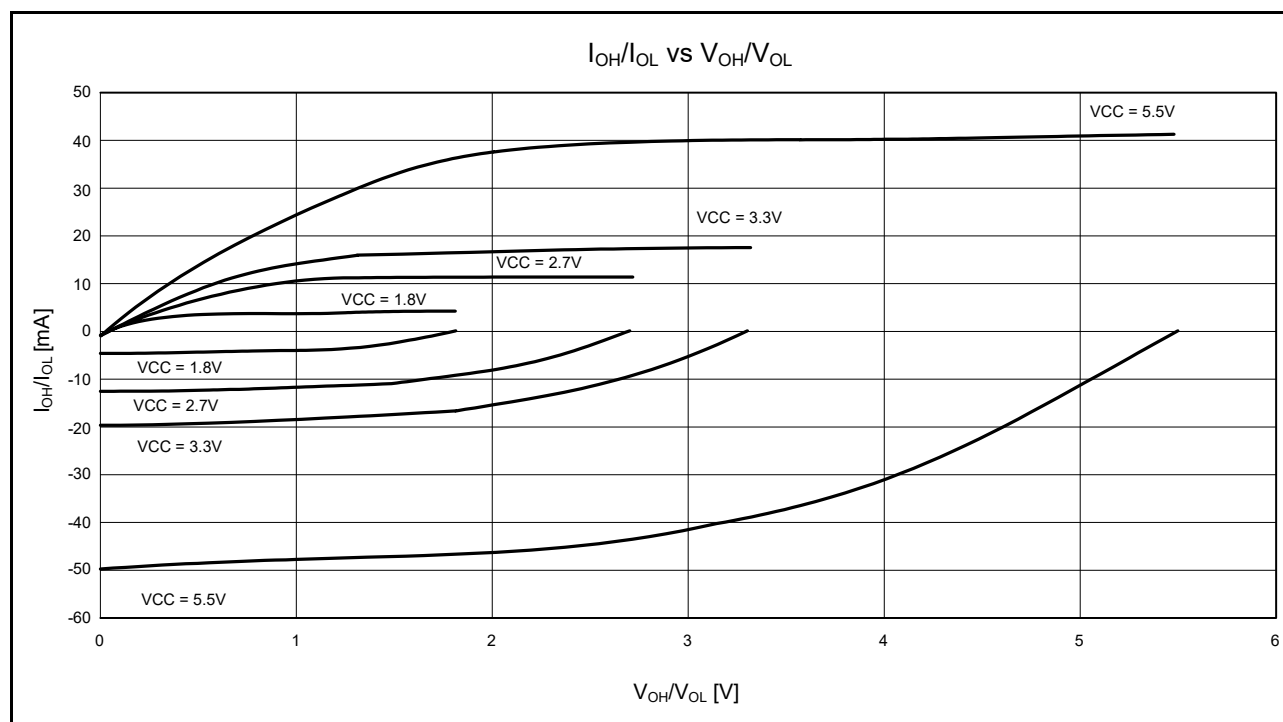


Figure 5.8 V_{OH}/V_{OL} and I_{OH}/I_{OL} Voltage Characteristics at $T_a = 25^\circ\text{C}$ When Normal Output is Selected (Reference Data)

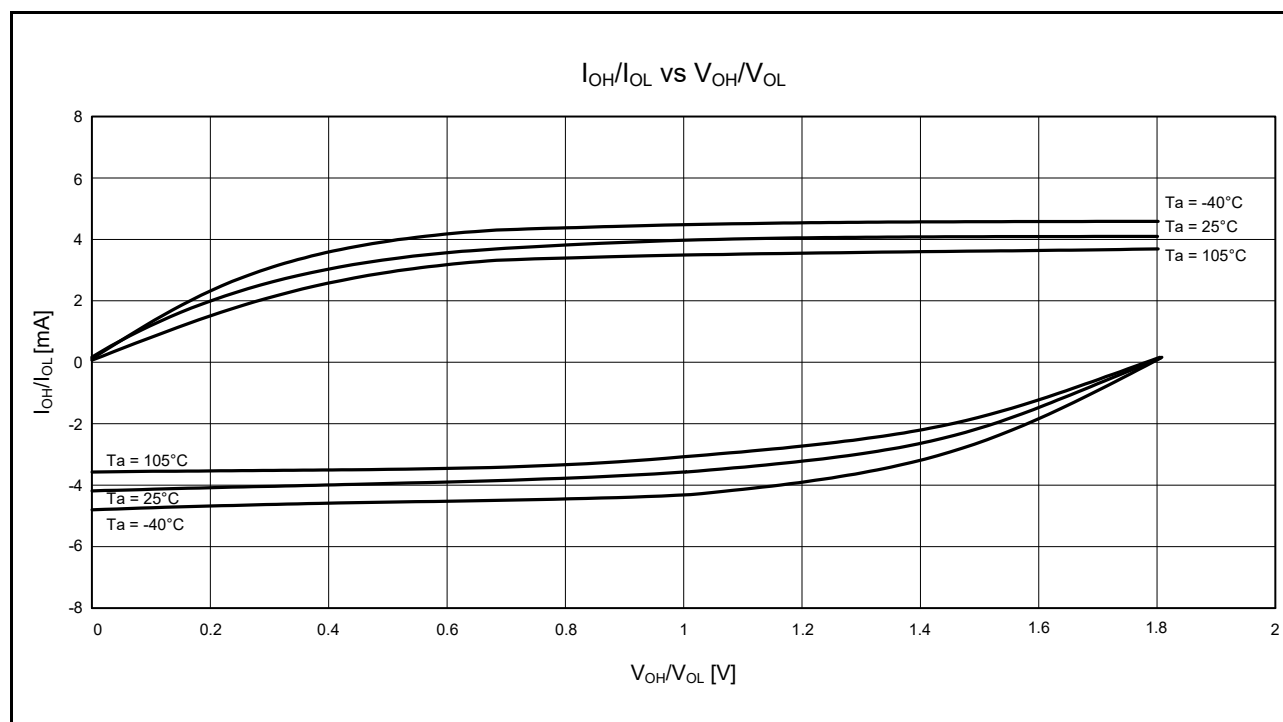


Figure 5.9 V_{OH}/V_{OL} and I_{OH}/I_{OL} Temperature Characteristics at $V_{CC} = 1.8\text{ V}$ When Normal Output is Selected (Reference Data)

Table 5.23 Operating Frequency Value (Low-Speed Operating Mode)Conditions: $1.8\text{ V} \leq VCC = VCC_USB = AVCC0 \leq 5.5\text{ V}$, $VSS = AVSS0 = VREFL0 = VSS_USB = 0\text{ V}$, $T_a = -40\text{ to }+105^\circ\text{C}$

Item		Symbol	VCC			Unit
			1.8 V ≤ VCC < 2.4 V	2.4 V ≤ VCC < 2.7 V	2.7 V ≤ VCC ≤ 5.5 V	
Maximum operating frequency*3	System clock (ICLK)	f _{max}	32.768			kHz
	FlashIF clock (FCLK)*1		32.768			
	Peripheral module clock (PCLKA)		32.768			
	Peripheral module clock (PCLKB)		32.768			
	Peripheral module clock (PCLKD)*2		32.768			
	External bus clock (BCLK)		32.768			
	BCLK pin output		32.768			

Note 1. Programming and erasing the flash memory is impossible.

Note 2. The A/D converter cannot be used.

Note 3. The maximum operating frequency listed above does not include errors of the external oscillator. For details on the range for the guaranteed operation, see Table 5.26, Clock Timing.

Table 5.24 BCLK Clock Timing (1)Conditions: $2.7\text{ V} \leq VCC = VCC_USB = AVCC0 \leq 5.5\text{ V}$, $VSS = AVSS0 = VREFL0 = VSS_USB = 0\text{ V}$, $f_{\text{BCLK}} \leq 32\text{ MHz}$ (BCLK pin output frequency $\leq 16\text{ MHz}$), $T_a = -40\text{ to }+105^\circ\text{C}$

Item	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
BCLK pin output cycle time	t_{Bcyc}	62.5	—	—	ns	Figure 5.22
BCLK pin output high pulse width	t_{CH}	15	—	—	ns	
BCLK pin output low pulse width	t_{CL}	15	—	—	ns	
BCLK pin output rise time	t_{Cr}	—	—	12	ns	
BCLK pin output fall time	t_{Cf}	—	—	12	ns	

Table 5.25 BCLK Clock Timing (2)Conditions: $1.8\text{ V} \leq VCC = VCC_USB = AVCC0 < 2.7\text{ V}$, $VSS = AVSS0 = VREFL0 = VSS_USB = 0\text{ V}$, $f_{\text{BCLK}} \leq 16\text{ MHz}$ (BCLK pin output frequency $\leq 8\text{ MHz}$), $T_a = -40\text{ to }+105^\circ\text{C}$

Item	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
BCLK pin output cycle time	t_{Bcyc}	125	—	—	ns	Figure 5.22
BCLK pin output high pulse width	t_{CH}	30	—	—	ns	
BCLK pin output low pulse width	t_{CL}	30	—	—	ns	
BCLK pin output rise time	t_{Cr}	—	—	25	ns	
BCLK pin output fall time	t_{Cf}	—	—	25	ns	

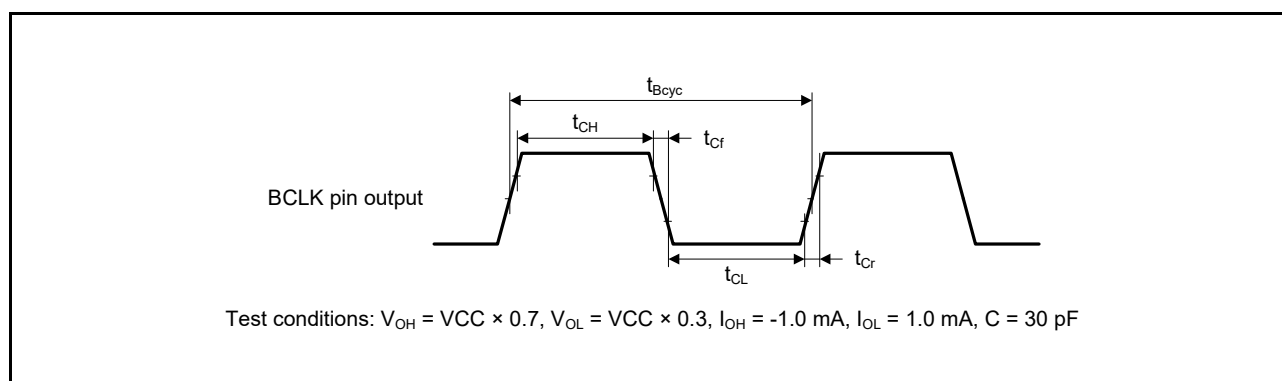


Figure 5.22 BCLK Pin Output Timing

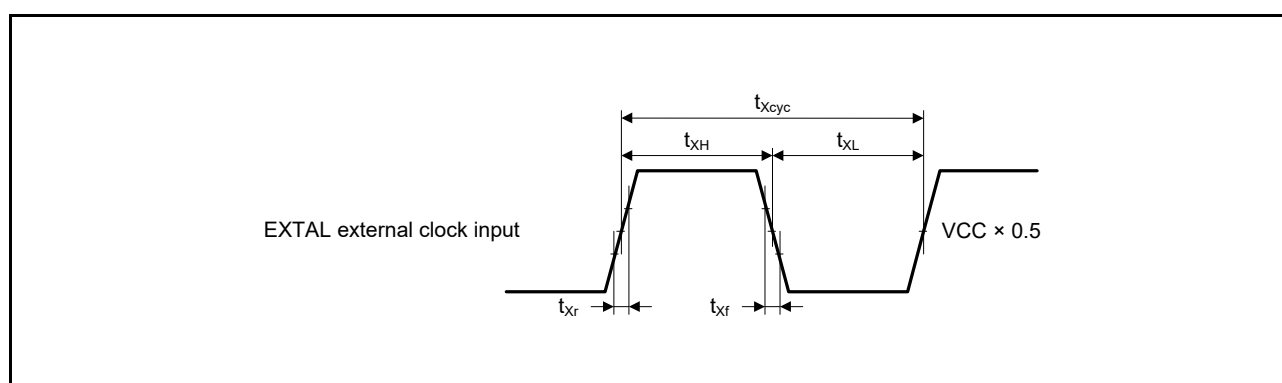


Figure 5.23 EXTAL External Clock Input Timing

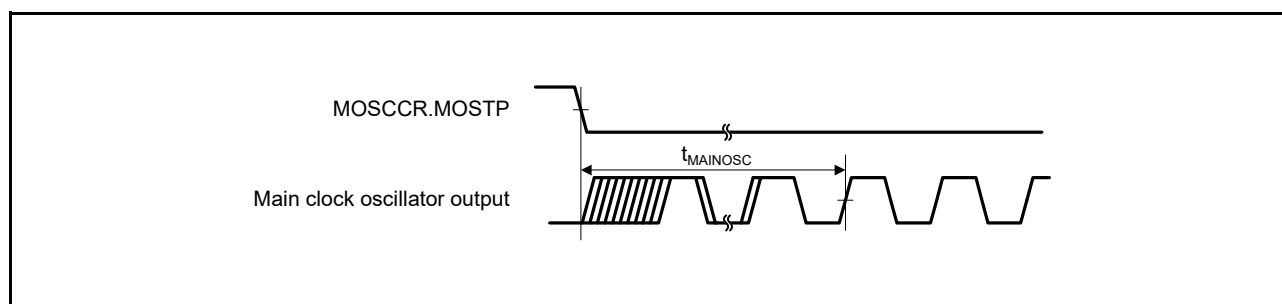


Figure 5.24 Main Clock Oscillation Start Timing

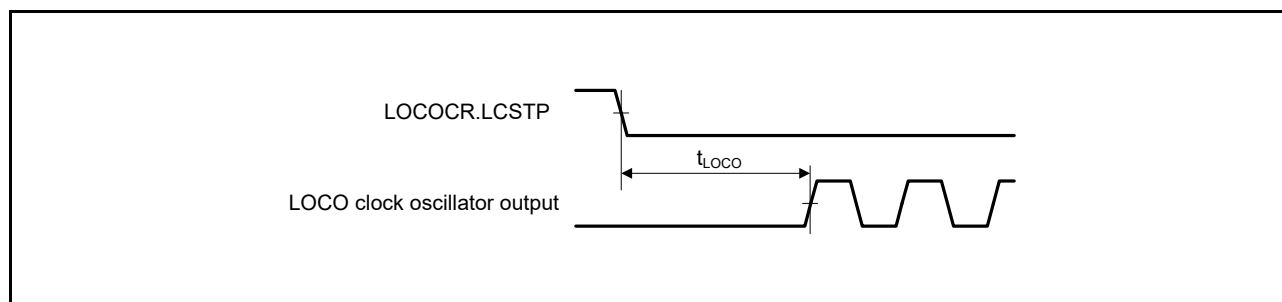


Figure 5.25 LOCO Clock Oscillation Start Timing

5.3.4 Control Signal Timing

Table 5.33 Control Signal Timing

Conditions: $1.8\text{ V} \leq VCC = VCC_USB = AVCC0 \leq 5.5\text{ V}$, $VSS = AVSS0 = VSS_USB = 0\text{ V}$, $T_a = -40\text{ to }+105^\circ\text{C}$

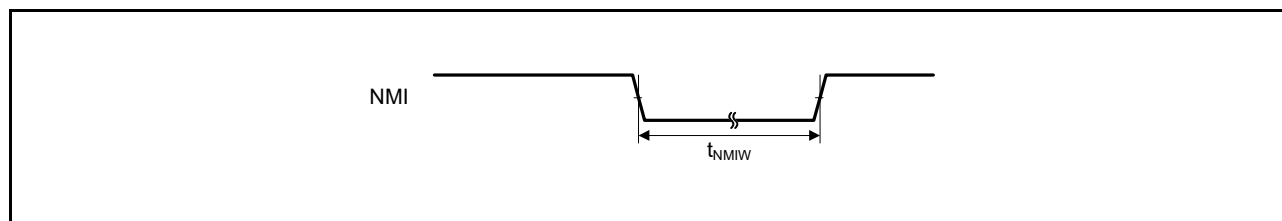
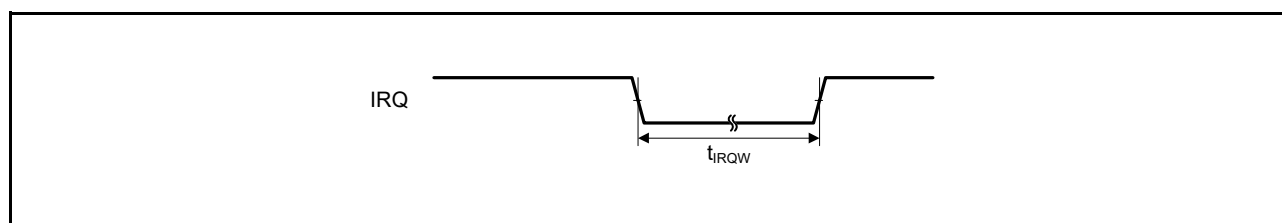
Item	Symbol	Min.	Typ.	Max.	Unit	Test Conditions	
NMI pulse width	t_{NMIW}	200	—	—	ns	NMI digital filter is disabled (NMIFLTE.NFLTEN = 0)	$t_{Pcyc} \times 2 \leq 200\text{ ns}$
		$t_{Pcyc} \times 2^{*1}$	—	—			$t_{Pcyc} \times 2 > 200\text{ ns}$
		200	—	—		NMI digital filter is enabled (NMIFLTE.NFLTEN = 1)	$t_{NMICK} \times 3 \leq 200\text{ ns}$
		$t_{NMICK} \times 3.5^{*2}$	—	—			$t_{NMICK} \times 3 > 200\text{ ns}$
IRQ pulse width	t_{IRQW}	200	—	—	ns	IRQ digital filter is disabled (IRQFLTE0.FLTENi = 0)	$t_{Pcyc} \times 2 \leq 200\text{ ns}$
		$t_{Pcyc} \times 2^{*1}$	—	—			$t_{Pcyc} \times 2 > 200\text{ ns}$
		200	—	—		IRQ digital filter is enabled (IRQFLTE0.FLTENi = 1)	$t_{IRQCK} \times 3 \leq 200\text{ ns}$
		$t_{IRQCK} \times 3.5^{*3}$	—	—			$t_{IRQCK} \times 3 > 200\text{ ns}$

Note: 200 ns minimum in software standby mode.

Note 1. t_{Pcyc} indicates the cycle of PCLKB.

Note 2. t_{NMICK} indicates the cycle of the NMI digital filter sampling clock.

Note 3. t_{IRQCK} indicates the cycle of the IRQi digital filter sampling clock (i = 0 to 7).

**Figure 5.36 NMI Interrupt Input Timing****Figure 5.37 IRQ Interrupt Input Timing**

5.3.5 Bus Timing

Table 5.34 Bus Timing (1)

Conditions: $2.7\text{ V} \leq V_{CC} = V_{CC_USB} = AV_{CC0} \leq 5.5\text{ V}$, $V_{SS} = AV_{SS0} = V_{SS_USB} = 0\text{ V}$,
 $f_{BCLK} \leq 32\text{ MHz}$ (BCLK pin output frequency $\leq 16\text{ MHz}$), $T_a = -40\text{ to }+105^\circ\text{C}$, $V_{OH} = V_{CC} \times 0.5$, $V_{OL} = V_{CC} \times 0.5$,
 $I_{OH} = -1.0\text{ mA}$, $I_{OL} = 1.0\text{ mA}$, $C_L = 30\text{ pF}$, when normal output is selected by the drive capacity control register

Item	Symbol	Min.	Max.	Unit	Test Conditions
Address delay time	t_{AD}	—	55	ns	Figure 5.38 to Figure 5.41
Byte control delay time	t_{BCD}	—	55	ns	
CS# delay time	t_{CSD}	—	55	ns	
RD# delay time	t_{RSD}	—	55	ns	
Read data setup time	t_{RDS}	40	—	ns	
Read data hold time	t_{RDH}	0	—	ns	
WR# delay time	t_{WRD}	—	55	ns	
Write data delay time	t_{WDD}	—	55	ns	
Write data hold time	t_{WDH}	0	—	ns	Figure 5.42
WAIT# setup time	t_{WTS}	40	—	ns	
WAIT# hold time	t_{WTH}	0	—	ns	

Table 5.35 Bus Timing (2)

Conditions: $1.8\text{ V} \leq V_{CC} = V_{CC_USB} = AV_{CC0} < 2.7\text{ V}$, $V_{SS} = AV_{SS0} = V_{SS_USB} = 0\text{ V}$,
 $f_{BCLK} \leq 16\text{ MHz}$ (BCLK pin output frequency $\leq 8\text{ MHz}$), $T_a = -40\text{ to }+105^\circ\text{C}$, $V_{OH} = V_{CC} \times 0.5$, $V_{OL} = V_{CC} \times 0.5$,
 $I_{OH} = -1.0\text{ mA}$, $I_{OL} = 1.0\text{ mA}$, $C_L = 30\text{ pF}$, when normal output is selected by the drive capacity control register

Item	Symbol	Min.	Max.	Unit	Test Conditions
Address delay time	t_{AD}	—	90	ns	Figure 5.38 to Figure 5.41
Byte control delay time	t_{BCD}	—	90	ns	
CS# delay time	t_{CSD}	—	90	ns	
RD# delay time	t_{RSD}	—	90	ns	
Read data setup time	t_{RDS}	60	—	ns	
Read data hold time	t_{RDH}	0	—	ns	
WR# delay time	t_{WRD}	—	90	ns	
Write data delay time	t_{WDD}	—	90	ns	
Write data hold time	t_{WDH}	0	—	ns	Figure 5.42
WAIT# setup time	t_{WTS}	60	—	ns	
WAIT# hold time	t_{WTH}	0	—	ns	

Table 5.39 Timing of On-Chip Peripheral Modules (2)

Conditions: $1.8\text{ V} \leq V_{CC} = V_{CC_USB} = AV_{CC0} \leq 5.5\text{ V}$, $V_{SS} = AV_{SS0} = V_{SS_USB} = 0\text{ V}$, $T_a = -40\text{ to }+105^\circ\text{C}$, $C = 30\text{ pF}$,
when high-drive output is selected by the drive capacity control register

Item				Symbol	Min.	Max.	Unit	Test Conditions
RSPI	RSPCK clock cycle	Master		t_{SPcyc}	2	4096	t_{Pcyc}^{*1}	Figure 5.54
		Slave			8	4096		
	RSPCK clock high pulse width	Master		t_{SPCKWH}	$(t_{SPcyc} - t_{SPCKr} - t_{SPCKf})/2 - 3$	—	ns	
		Slave			$(t_{SPcyc} - t_{SPCKr} - t_{SPCKf})/2$	—		
	RSPCK clock low pulse width	Master		t_{SPCKWL}	$(t_{SPcyc} - t_{SPCKr} - t_{SPCKf})/2 - 3$	—	ns	
		Slave			$(t_{SPcyc} - t_{SPCKr} - t_{SPCKf})/2$	—		
	RSPCK clock rise/fall time	Output	2.7 V or above	t_{SPCKr} t_{SPCKf}	—	10	ns	
			1.8 V or above		—	15		
		Input			—	1	μ s	
	Data input setup time	Master	2.7 V or above	t_{SU}	10	—	ns	Figure 5.55 to Figure 5.58
			1.8 V or above		30	—		
		Slave			$25 - t_{Pcyc}$	—		
	Data input hold time	Master	RSPCK set to a division ratio other than PCLKB divided by 2	t_H	t_{Pcyc}	—	ns	
			RSPCK set to PCLKB divided by 2	t_{HF}	0	—		
		Slave		t_H	$20 + 2 \times t_{Pcyc}$	—		
	SSL setup time	Master		t_{LEAD}	$-30 + N^2 \times t_{SPcyc}$	—	ns	
		Slave			2	—	t_{Pcyc}	
	SSL hold time	Master		t_{LAG}	$-30 + N^3 \times t_{SPcyc}$	—	ns	
		Slave			2	—	t_{Pcyc}	
	Data output delay time	Master	2.7 V or above	t_{OD}	—	14	ns	
1.8 V or above			—		30			
Slave		2.7 V or above	—		$3 \times t_{Pcyc} + 65$			
		1.8 V or above	—		$3 \times t_{Pcyc} + 105$			
Data output hold time	Master		t_{OH}	0	—	ns		
	Slave			0	—			
Successive transmission delay time	Master		t_{TD}	$t_{SPcyc} + 2 \times t_{Pcyc}$	$8 \times t_{SPcyc} + 2 \times t_{Pcyc}$	ns		
	Slave			$4 \times t_{Pcyc}$	—			
MOSI and MISO rise/fall time	Output	2.7 V or above	t_{Dr} , t_{Df}	—	10	ns		
		1.8 V or above		—	15			
	Input			—	1	μ s		
SSL rise/fall time	Output	2.7 V or above	t_{SSLr} , t_{SSLf}	—	10	ns		
		1.8 V or above		—	15	ns		
	Input			—	1	μ s		
Slave access time		2.7 V or above	t_{SA}	—	6	t_{Pcyc}	Figure 5.57, Figure 5.58	
		1.8 V or above		—	7			
Slave output release time		2.7 V or above	t_{REL}	—	5	t_{Pcyc}		
		1.8 V or above		—	6			

Note 1. t_{Pcyc} : PCLK cycle

Note 2. N: An integer from 1 to 8 that can be set by the RSPI clock delay register (SPCKD)

Note 3. N: An integer from 1 to 8 that can be set by the RSPI slave select negation delay register (SSLND)

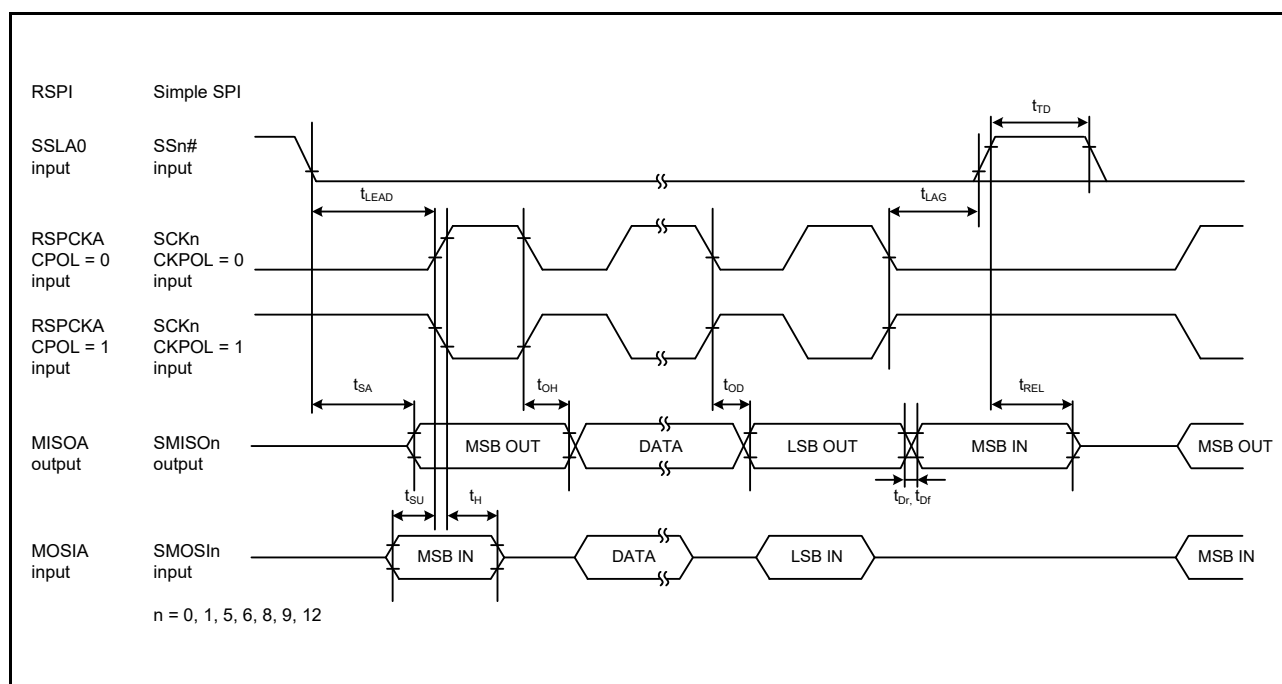


Figure 5.57 RSPI Timing (Slave, CPHA = 0) and Simple SPI Clock Timing (Slave, CKPH = 1)

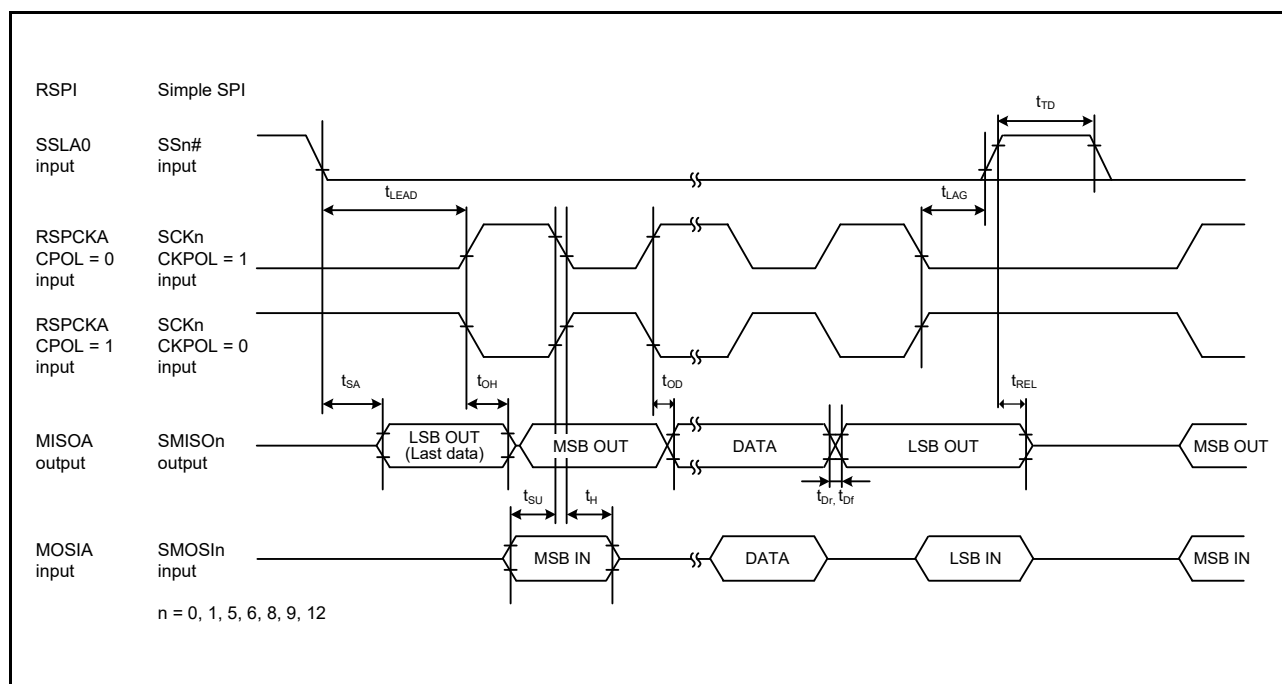


Figure 5.58 RSPI Timing (Slave, CPHA = 1) and Simple SPI Clock Timing (Slave, CKPH = 0)

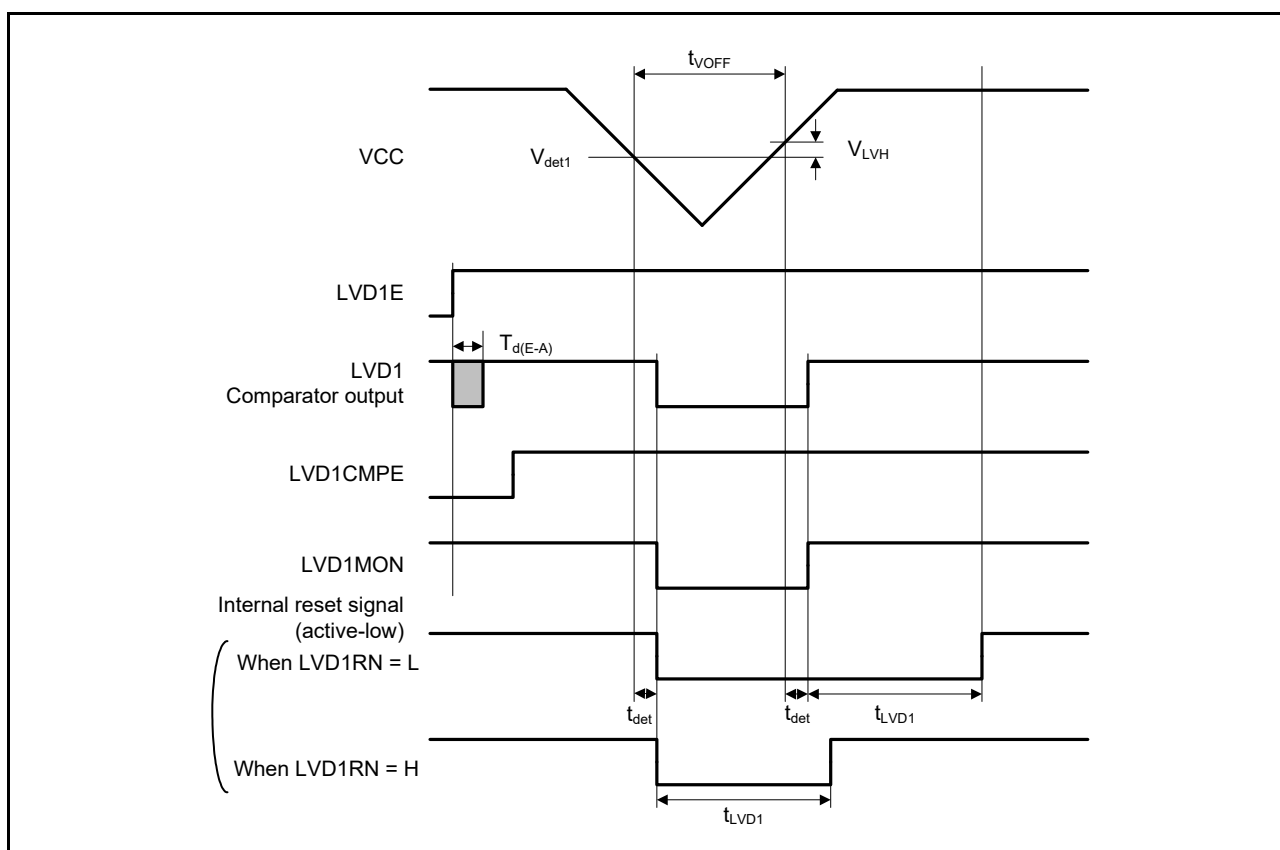
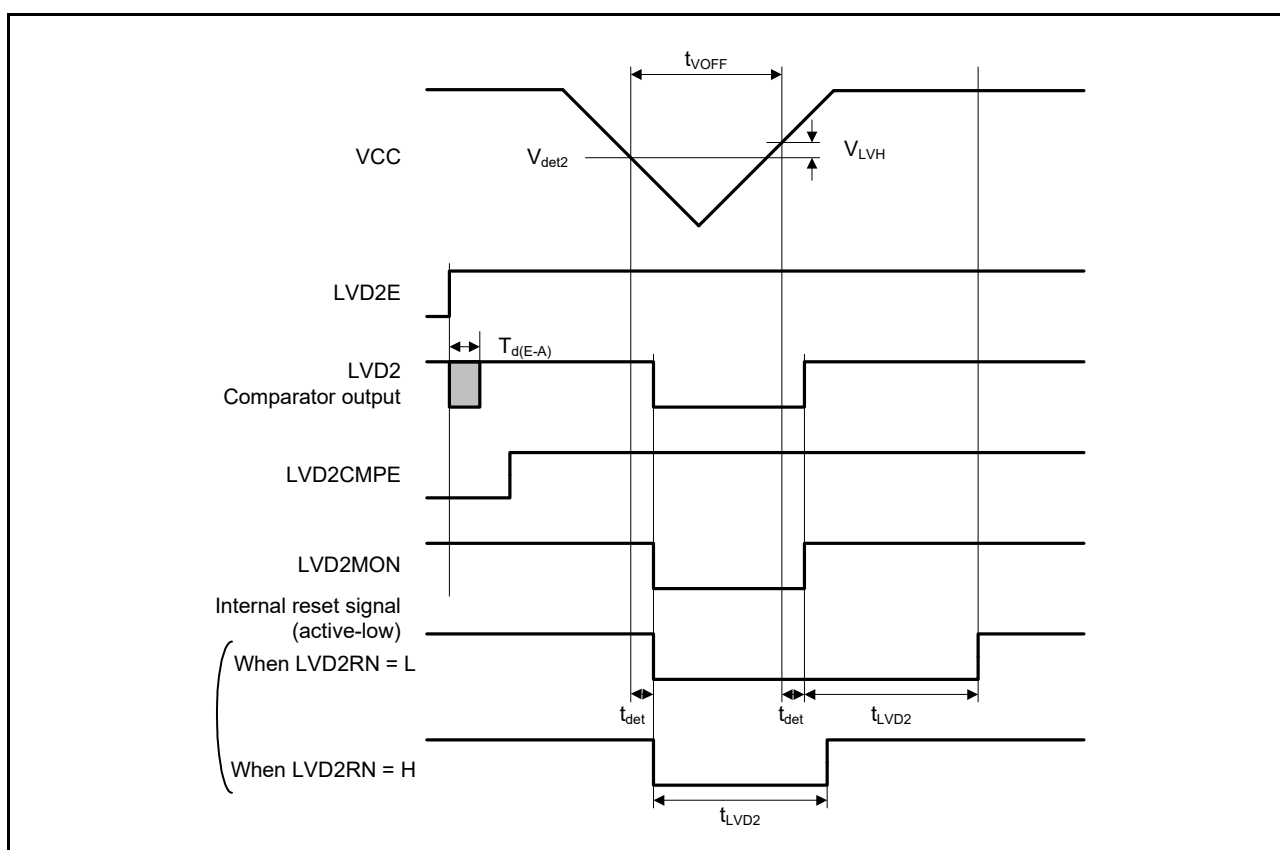
Table 5.47 A/D Conversion Characteristics (2)

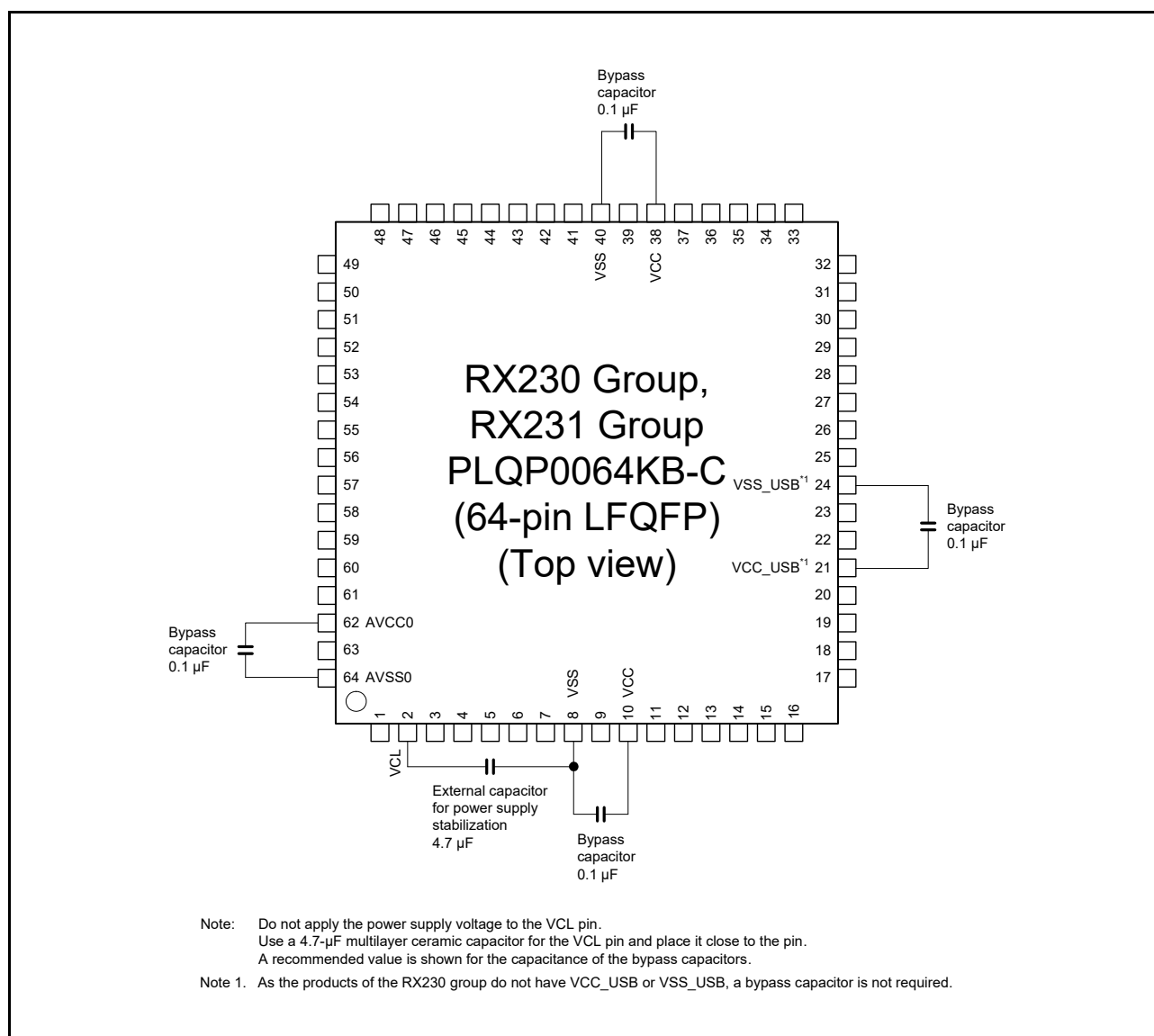
Conditions: $2.4\text{ V} \leq V_{CC} = V_{CC_USB} = AV_{CC0} \leq 5.5\text{ V}$, $2.4\text{ V} \leq V_{REFH0} \leq AV_{CC0}$, reference voltage = V_{REFH0} selected,
 $V_{SS} = AV_{SS0} = V_{REFL0} = V_{SS_USB} = 0\text{ V}$, $T_a = -40\text{ to }+105^\circ\text{C}$

Item		Min.	Typ.	Max.	Unit	Test Conditions
Frequency		1	—	32	MHz	
Resolution		—	—	12	Bit	
Conversion time*1 (Operation at PCLKD = 32 MHz)	Permissible signal source impedance (Max.) = 1.3 kΩ	1.41	—	—	μs	High-precision channel The ADCSR.ADHSC bit is 0 The ADSSTRn register is 0Dh
		2.25	—	—		Normal-precision channel The ADCSR.ADHSC bit is 0 The ADSSTRn register is 28h
Analog input capacitance	Cs	—	—	15	pF	Pin capacitance included Figure 5.68
Analog input resistance	Rs	—	—	2.5	kΩ	Figure 5.68
Offset error		—	±0.5	±4.5	LSB	
Full-scale error		—	±0.75	±4.5	LSB	
Quantization error		—	±0.5	—	LSB	
Absolute accuracy		—	±1.25	±5.0	LSB	High-precision channel
				±8.0	LSB	Other than above
DNL differential non-linearity error		—	±1.0	—	LSB	
INL integral non-linearity error		—	±1.0	±4.5	LSB	

Note: The characteristics apply when no pin functions other than A/D converter input are used. Absolute accuracy includes quantization errors. Offset error, full-scale error, DNL differential non-linearity error, and INL integral non-linearity error do not include quantization errors.

Note 1. The conversion time is the sum of the sampling time and the comparison time. As the test conditions, the number of sampling states is indicated.

Figure 5.76 Voltage Detection Circuit Timing (V_{det1})Figure 5.77 Voltage Detection Circuit Timing (V_{det2})

**Figure 5.81 Connecting Capacitors (64 Pins)**

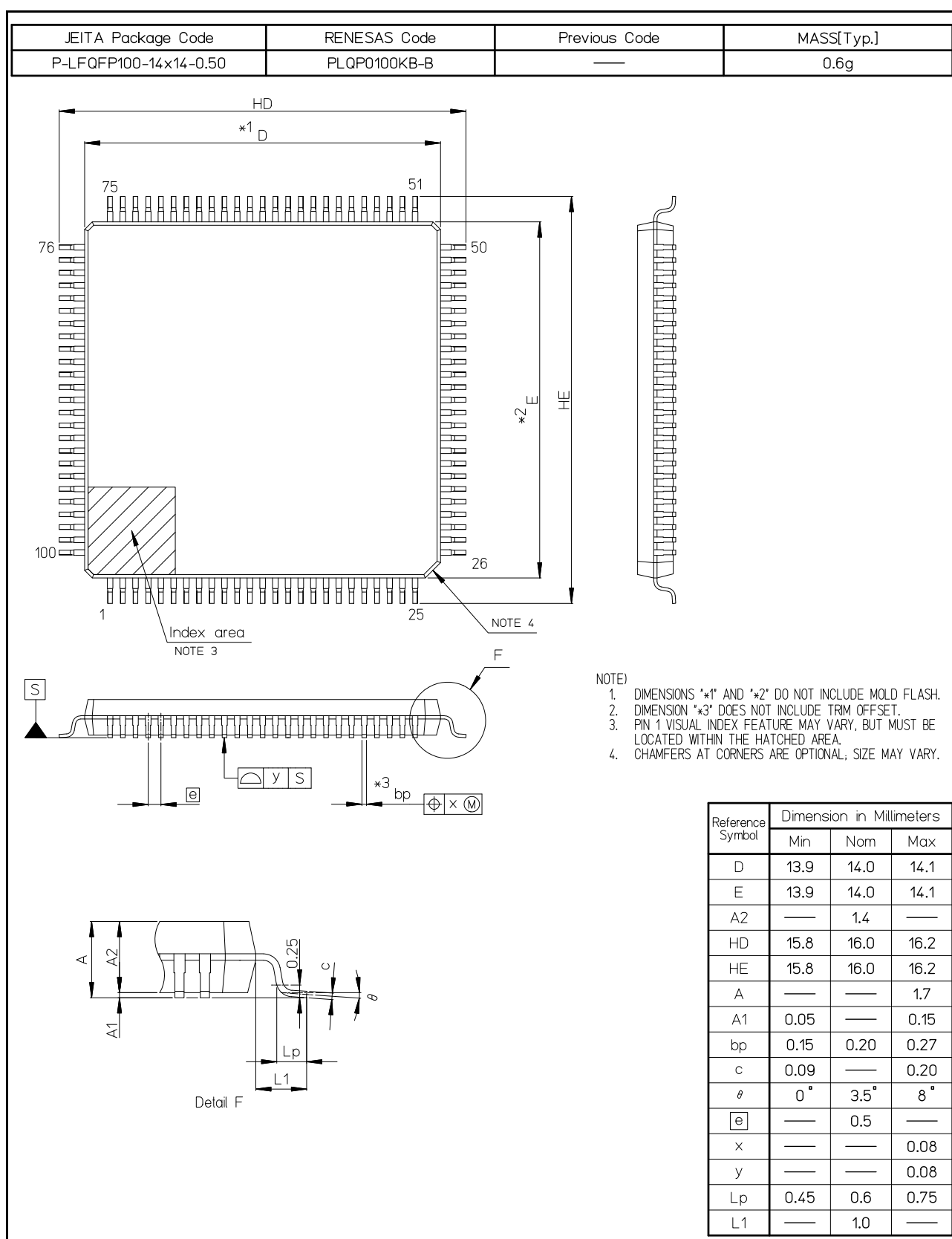


Figure B 100-Pin LFQFP (PLQP0100KB-B)

NOTES FOR CMOS DEVICES

- (1) **VOLTAGE APPLICATION WAVEFORM AT INPUT PIN:** Waveform distortion due to input noise or a reflected wave may cause malfunction. If the input of the CMOS device stays in the area between V_{IL} (MAX) and V_{IH} (MIN) due to noise, etc., the device may malfunction. Take care to prevent chattering noise from entering the device when the input level is fixed, and also in the transition period when the input level passes through the area between V_{IL} (MAX) and V_{IH} (MIN).
- (2) **HANDLING OF UNUSED INPUT PINS:** Unconnected CMOS device inputs can be cause of malfunction. If an input pin is unconnected, it is possible that an internal input level may be generated due to noise, etc., causing malfunction. CMOS devices behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using pull-up or pull-down circuitry. Each unused pin should be connected to VDD or GND via a resistor if there is a possibility that it will be an output pin. All handling related to unused pins must be judged separately for each device and according to related specifications governing the device.
- (3) **PRECAUTION AGAINST ESD:** A strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it when it has occurred. Environmental control must be adequate. When it is dry, a humidifier should be used. It is recommended to avoid using insulators that easily build up static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work benches and floors should be grounded. The operator should be grounded using a wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with mounted semiconductor devices.
- (4) **STATUS BEFORE INITIALIZATION:** Power-on does not necessarily define the initial status of a MOS device. Immediately after the power source is turned ON, devices with reset functions have not yet been initialized. Hence, power-on does not guarantee output pin levels, I/O settings or contents of registers. A device is not initialized until the reset signal is received. A reset operation must be executed immediately after power-on for devices with reset functions.
- (5) **POWER ON/OFF SEQUENCE:** In the case of a device that uses different power supplies for the internal operation and external interface, as a rule, switch on the external power supply after switching on the internal power supply. When switching the power supply off, as a rule, switch off the external power supply and then the internal power supply. Use of the reverse power on/off sequences may result in the application of an overvoltage to the internal elements of the device, causing malfunction and degradation of internal elements due to the passage of an abnormal current. The correct power on/off sequence must be judged separately for each device and according to related specifications governing the device.
- (6) **INPUT OF SIGNAL DURING POWER OFF STATE :** Do not input signals or an I/O pull-up power supply while the device is not powered. The current injection that results from input of such a signal or I/O pull-up power supply may cause malfunction and the abnormal current that passes in the device at this time may cause degradation of internal elements. Input of signals during the power off state must be judged separately for each device and according to related specifications governing the device.